



# STV160NF02L

## N-CHANNEL 20V - 0.0016Ω - 160A PowerSO-10 STripFET™ II POWER MOSFET

| TYPE        | V <sub>DSS</sub> | R <sub>DS(on)</sub> | I <sub>D</sub> |
|-------------|------------------|---------------------|----------------|
| STV160NF02L | 20 V             | < 0.0025 Ω          | 160 A          |

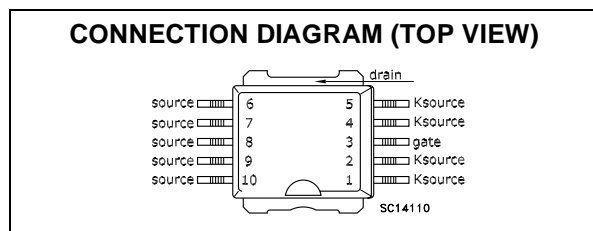
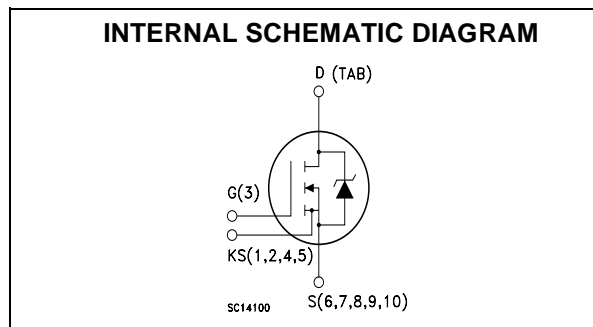
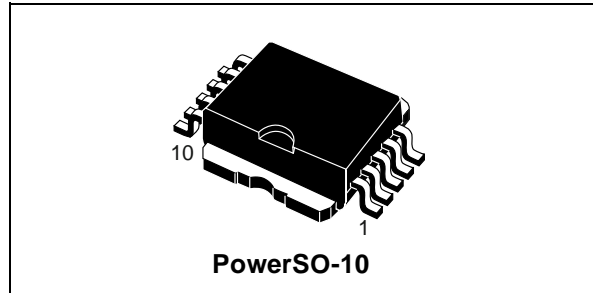
- TYPICAL R<sub>DS(on)</sub> = 0.0016 Ω
- LOW THRESHOLD DRIVE
- ULTRA LOW ON-RESISTANCE
- ULTRA FAST SWITCHING
- 100% AVALANCHE TESTED
- VERY LOW GATE CHARGE
- LOW PROFILE, VERY LOW PARASITIC INDUCTANCE PowerSO-10 PACKAGE

### DESCRIPTION

The **STV160NF02L** represents the second generation of Application Specific STMicroelectronics well established STripFET™ process based on a very unique strip layout design. The resulting MOSFET shows unrivalled high packing density with ultra low on-resistance and superior switching characteristics. Process simplification also translates into improved manufacturing reproducibility. This device is particularly suitable for high current, low voltage switching application where efficiency is crucial

### APPLICATIONS

- BUCK CONVERTERS IN HIGH PERFORMANCE TELECOM AND VRMs DC-DC CONVERTERS



### ABSOLUTE MAXIMUM RATINGS

| Symbol              | Parameter  | Value      | Unit |
|---------------------|--|------------|------|
| V <sub>DS</sub>     | Drain-source Voltage (V <sub>GS</sub> = 0)           | 20         | V    |
| V <sub>DGR</sub>    | Drain-gate Voltage (R <sub>GS</sub> = 20 kΩ)         | 20         | V    |
| V <sub>GS</sub>     | Gate- source Voltage                                 | ± 15       | V    |
| I <sub>D</sub> (**) | Drain Current (continuous) at T <sub>C</sub> = 25°C  | 160        | A    |
| I <sub>D</sub>      | Drain Current (continuous) at T <sub>C</sub> = 100°C | 113        | A    |
| I <sub>DM</sub> (●) | Drain Current (pulsed)                               | 640        | A    |
| P <sub>TOT</sub>    | Total Dissipation at T <sub>C</sub> = 25°C           | 210        | W    |
|                     | Derating Factor                                      | 1.4        | W/°C |
| E <sub>AS</sub> (1) | Single Pulse Avalanche Energy                        | 1.5        | J    |
| T <sub>stg</sub>    | Storage Temperature                                  | -65 to 175 | °C   |
| T <sub>j</sub>      | Max. Operating Junction Temperature                  | 175        | °C   |

(●) Pulse width limited by safe operating area

(1) Starting T<sub>j</sub>=25°C , I<sub>D</sub> = 80A, V<sub>DD</sub> = 20V

(\*\*) Limited only maximum junction temperature allowed by PowerSO-10

## STV160NF02L

### THERMAL DATA

|                |  |      |      |
|----------------|--|------|------|
| Rthj-case      | Thermal Resistance Junction-case Max           | 0.71 | °C/W |
| Rthj-amb       | Thermal Resistance Junction-ambient Max        | 50   | °C/W |
| T <sub>I</sub> | Maximum Lead Temperature For Soldering Purpose | 300  | °C   |

### ELECTRICAL CHARACTERISTICS (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

| Symbol               | Parameter   | Test Conditions   | Min. | Typ. | Max.    | Unit     |
|----------------------|---|---|------|------|---------|----------|
| V <sub>(BR)DSS</sub> | Drain-source Breakdown Voltage                        | I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0  | 20   |      |         | V        |
| I <sub>DSS</sub>     | Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0) | V <sub>DS</sub> = Max Rating<br>V <sub>DS</sub> = Max Rating, T <sub>C</sub> = 125 °C |      |      | 1<br>10 | μA<br>μA |
| I <sub>GSS</sub>     | Gate-body Leakage Current (V <sub>DS</sub> = 0)       | V <sub>GS</sub> = ± 15 V  |      |      | ±100    | nA       |

### ON (1)

| Symbol              | Parameter                         | Test Conditions  | Min. | Typ.                      | Max.  | Unit   |
|---------------------|-----------------------------------|--|------|---------------------------|---|--|
| V <sub>GS(th)</sub> | Gate Threshold Voltage            | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA   | 1    |                           |   | V  |
| R <sub>DS(on)</sub> | Static Drain-source On Resistance | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 80 A<br>V <sub>GS</sub> = 10 V, I <sub>D</sub> = 45 A<br>V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A<br>V <sub>GS</sub> = 8 V, I <sub>D</sub> = 80 A<br>V <sub>GS</sub> = 5 V, I <sub>D</sub> = 40 A<br>V <sub>GS</sub> = 10 V, I <sub>D</sub> =80 A; T <sub>j</sub> = 175 °C<br>V <sub>GS</sub> = 8 V, I <sub>D</sub> =80 A; T <sub>j</sub> = 175 °C<br>V <sub>GS</sub> = 5 V, I <sub>D</sub> =40 A; T <sub>j</sub> = 175 °C | 1.35 | 1.6<br>1.56<br>1.7<br>3.5 | 2.5<br>2.5<br>2.5<br>3.5<br>6<br>5.7<br>7<br>11.4 | mΩ<br>mΩ<br>mΩ<br>mΩ<br>mΩ<br>mΩ<br>mΩ<br>mΩ |
| I <sub>D(on)</sub>  | On State Drain Current            | V <sub>DS</sub> > I <sub>D(on)</sub> × R <sub>DS(on)max</sub> ,<br>V <sub>GS</sub> = 10V   | 160  |                           |   | A  |

### DYNAMIC

| Symbol   | Parameter   | Test Conditions   | Min.                                      | Typ.                  | Max. | Unit           |
|--|---|---|---|-----------------------|------|----------------|
| g <sub>fs</sub> (1)                                      | Forward Transconductance  | V <sub>DS</sub> > I <sub>D(on)</sub> × R <sub>DS(on)max</sub> ,<br>I <sub>D</sub> = 80A |   | 210                   |      | S              |
| R <sub>g</sub>   | Gate resistance   | V <sub>DS</sub> = 0 V, f = 1 MHz, V <sub>GS</sub> = 0                                   |   | 0.5                   |      | Ω              |
| C <sub>iss</sub><br>C <sub>oss</sub><br>C <sub>rss</sub> | Input Capacitance<br>Output Capacitance<br>Reverse Transfer Capacitance | V <sub>DS</sub> = 15 V, f = 1 MHz, V <sub>GS</sub> = 0                                  |   | 4800<br>3000<br>680   |      | pF<br>pF<br>pF |
| C <sub>iss</sub><br>C <sub>oss</sub><br>C <sub>rss</sub> | Input Capacitance<br>Output Capacitance<br>Reverse Transfer Capacitance | V <sub>DS</sub> = 0 V, f = 1 MHz, V <sub>GS</sub> = 0                                   |   | 7000<br>12300<br>4200 |      | pF<br>pF<br>pF |
| L <sub>S</sub>   | Internal Source Inductance  | From the Lead End (6mm from Package Body) to the Die Center                             |   | 4                     |      | nH             |
| L <sub>D</sub>   | Internal Drain Inductance   |   | Not Available on Surface Mounting Package |                       |      |                |

**ELECTRICAL CHARACTERISTICS (CONTINUED)**

**SWITCHING ON**

| Symbol      | Parameter          | Test Conditions  | Min. | Typ. | Max. | Unit |
|-------------|--------------------|--|------|------|------|------|
| $t_{d(on)}$ | Turn-on Delay Time | $V_{DD} = 10\text{ V}$ , $I_D = 80\text{ A}$                               |      | 28   |      | ns   |
| $t_r$       | Rise Time          | $R_G = 4.7\Omega$ , $V_{GS} = 10\text{ V}$<br>(see test circuit, Figure 3) |      | 800  |      | ns   |
| $Q_g$       | Total Gate Charge  | $V_{DD} = 16\text{ V}$ , $I_D = 160\text{ A}$ ,                            |      | 115  | 160  | nC   |
| $Q_{gs}$    | Gate-Source Charge | $V_{GS} = 10\text{ V}$   |      | 15   |      | nC   |
| $Q_{gd}$    | Gate-Drain Charge  |  |      | 45   |      | nC   |

**SWITCHING OFF**

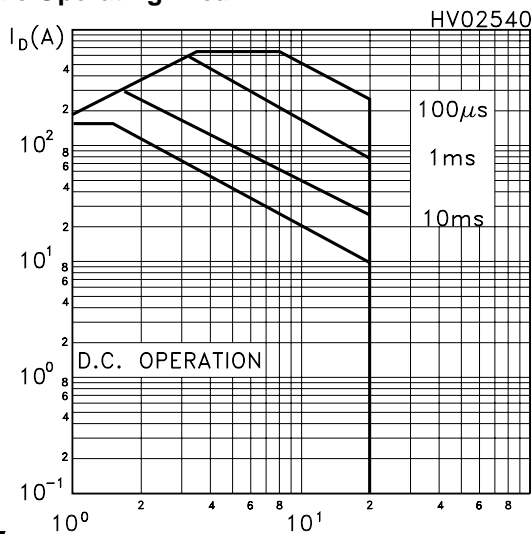
| Symbol        | Parameter             | Test Conditions  | Min. | Typ. | Max. | Unit |
|---------------|-----------------------|--|------|------|------|------|
| $t_{d(off)}$  | Turn-off-Delay Time   | $V_{DD} = 10\text{ V}$ , $I_D = 80\text{ A}$ ,                             |      | 80   |      | ns   |
| $t_f$         | Fall Time             | $R_G = 4.7\Omega$ , $V_{GS} = 10\text{ V}$<br>(see test circuit, Figure 5) |      | 240  |      | ns   |
| $t_{d(off)}$  | Turn-off Delay Time   | $V_{clamp} = 16\text{ V}$ , $I_D = 40\text{ A}$                            |      | 80   |      | ns   |
| $t_{r(Voff)}$ | Off-voltage Rise Time | $R_G = 4.7\Omega$ , $V_{GS} = 10\text{ V}$                                 |      | 40   |      | ns   |
| $t_f$         | Fall Time             |  |      | 140  |      | ns   |
| $t_c$         | Cross-over Time       |  |      | 200  |      | ns   |

**SOURCE DRAIN DIODE**

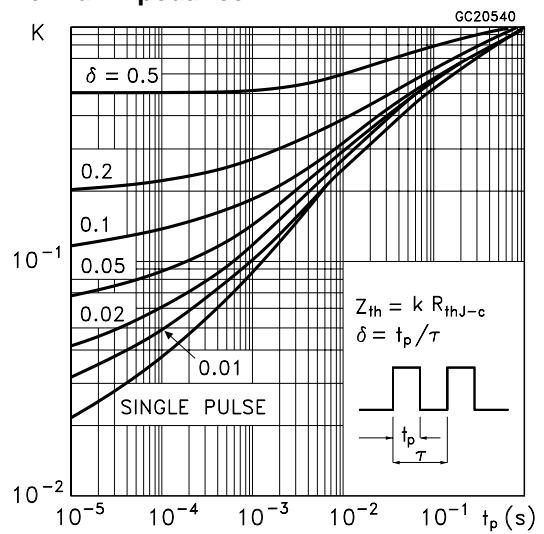
| Symbol       | Parameter                     | Test Conditions   | Min. | Typ. | Max. | Unit |
|--------------|-------------------------------|---|------|------|------|------|
| $I_{SD}$     | Source-drain Current          |   |      |      | 160  | A    |
| $I_{SDM(1)}$ | Source-drain Current (pulsed) |   |      |      | 640  | A    |
| $V_{SD(2)}$  | Forward On Voltage            | $I_{SD} = 160\text{ A}$ , $V_{GS} = 0$                        |      |      | 1.5  | V    |
| $t_{rr}$     | Reverse Recovery Time         | $I_{SD} = 80\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ , |      | 90   |      | ns   |
| $Q_{rr}$     | Reverse Recovery Charge       | $V_{DD} = 15\text{ V}$ , $T_j = 25^\circ\text{C}$             |      | 225  |      | nC   |
| $I_{RRM}$    | Reverse Recovery Current      | (see test circuit, Figure 5)                                  |      | 5    |      | A    |

Note: 1. Pulsed: Pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5 %.  
 2. Pulse width limited by safe operating area.

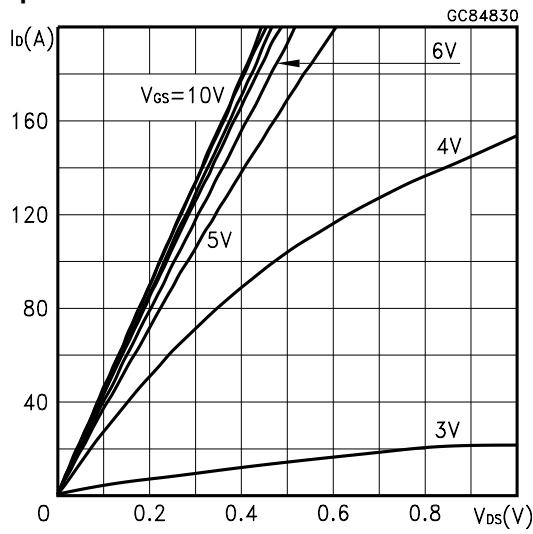
**Safe Operating Area**



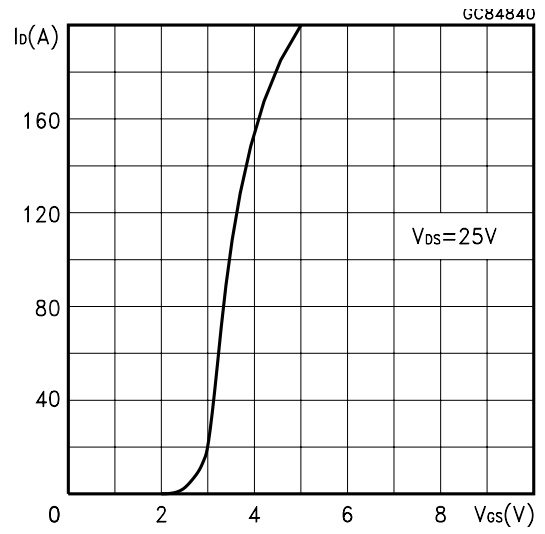
**Thermal Impedance**



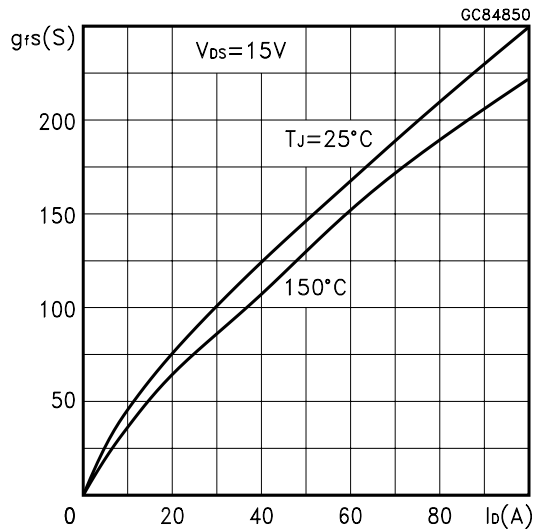
Output Characteristics



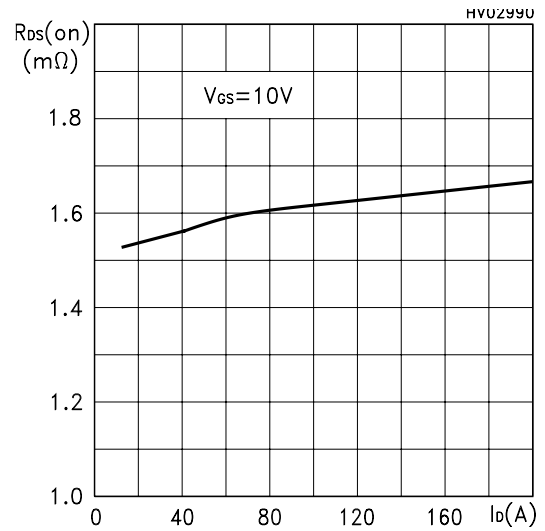
Transfer Characteristics



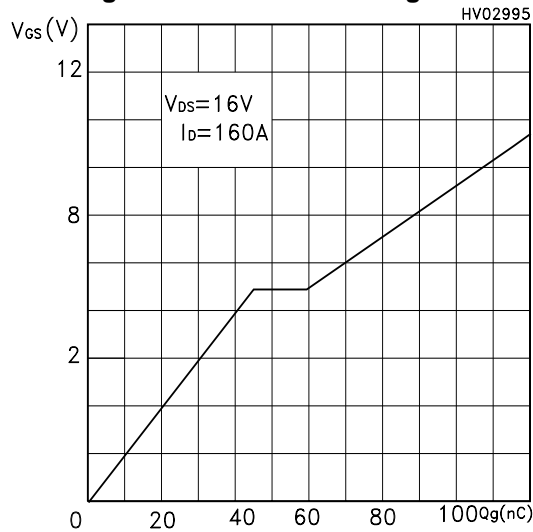
Transconductance



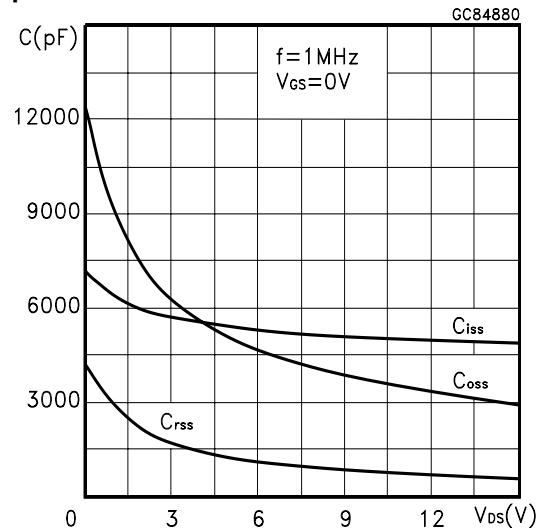
Static Drain-Source On Resistance



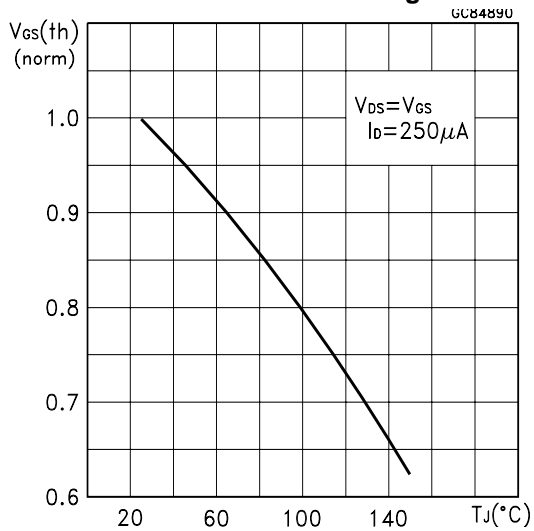
Gate Charge vs Gate-source Voltage



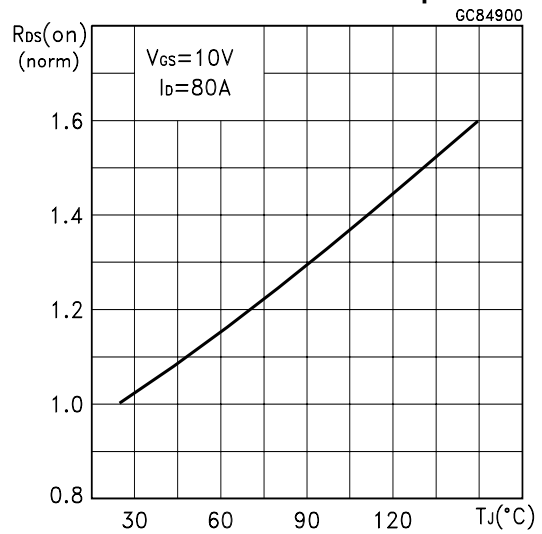
Capacitance Variations



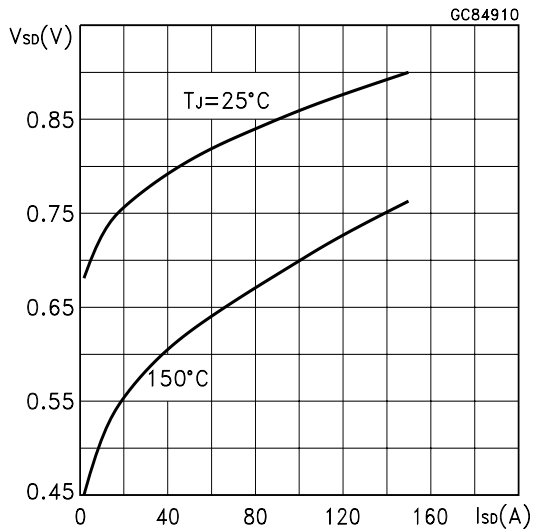
Normalized Gate Threshold Voltage vs Temp.



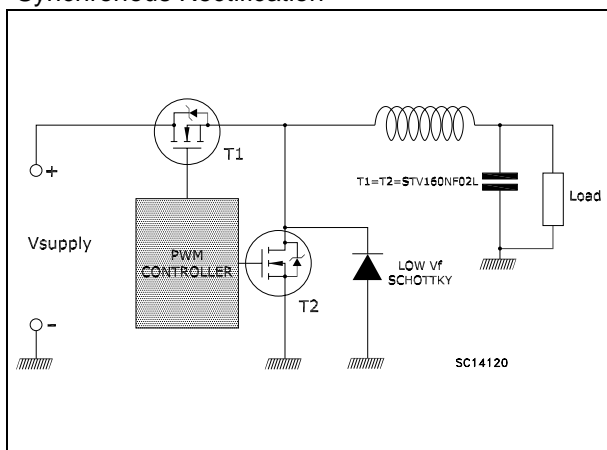
Normalized On Resistance vs Temperature



Source-drain Diode Forward Characteristics



Basic Schematic For Motherboard VRM With Synchronous Rectification



Basic Schematic Mosfets Switch Used In Secondary Side Of a Froward Convert

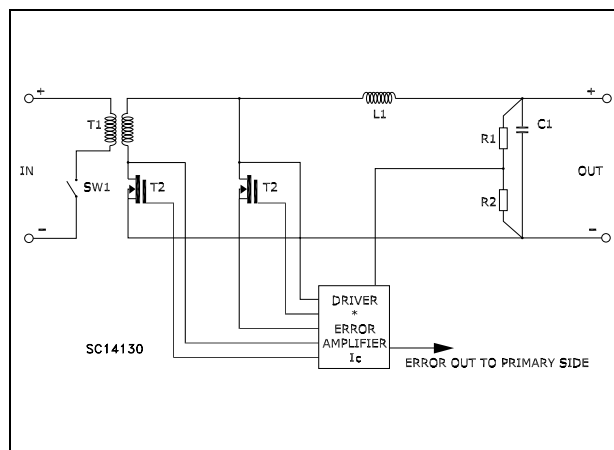


Fig. 1: Unclamped Inductive Load Test Circuit

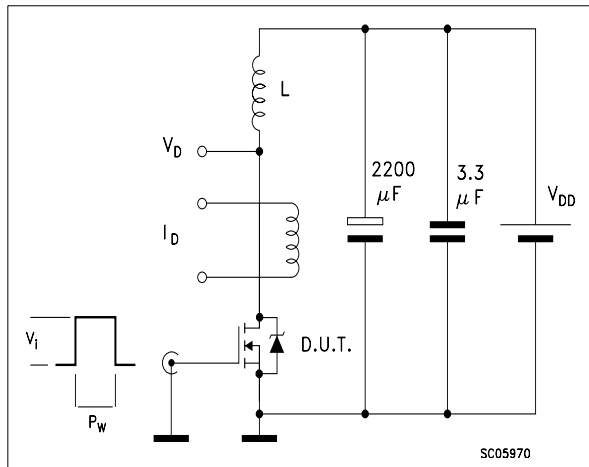


Fig. 2: Unclamped Inductive Waveform

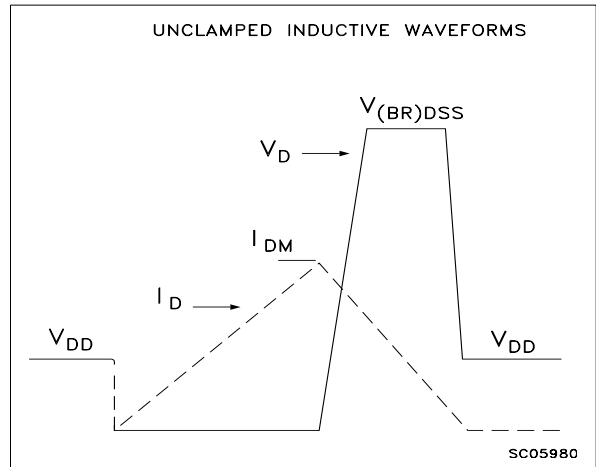


Fig. 3: Switching Times Test Circuit For Resistive Load

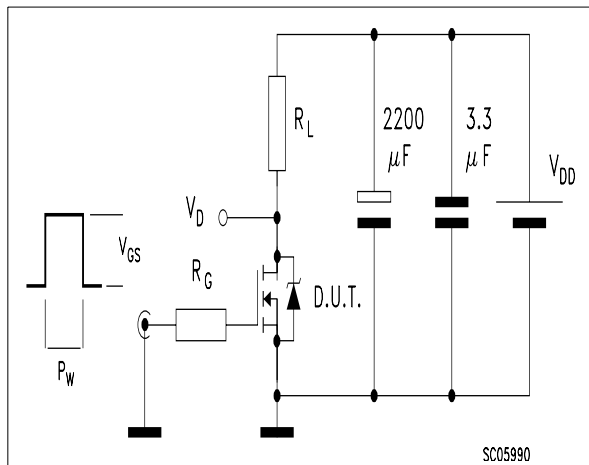


Fig. 4: Gate Charge test Circuit

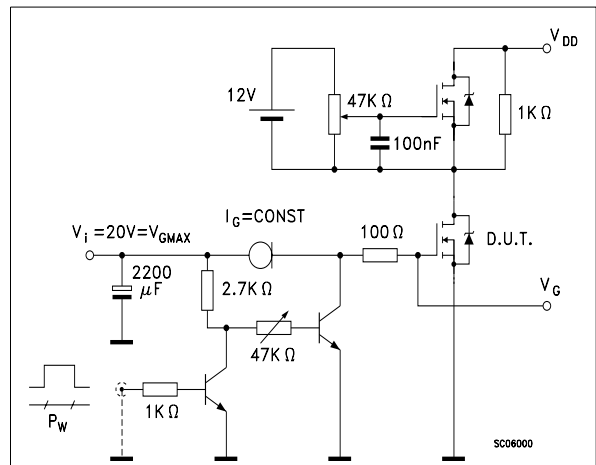
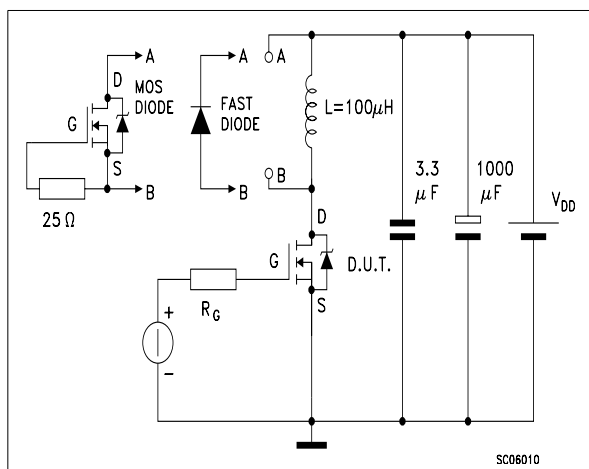
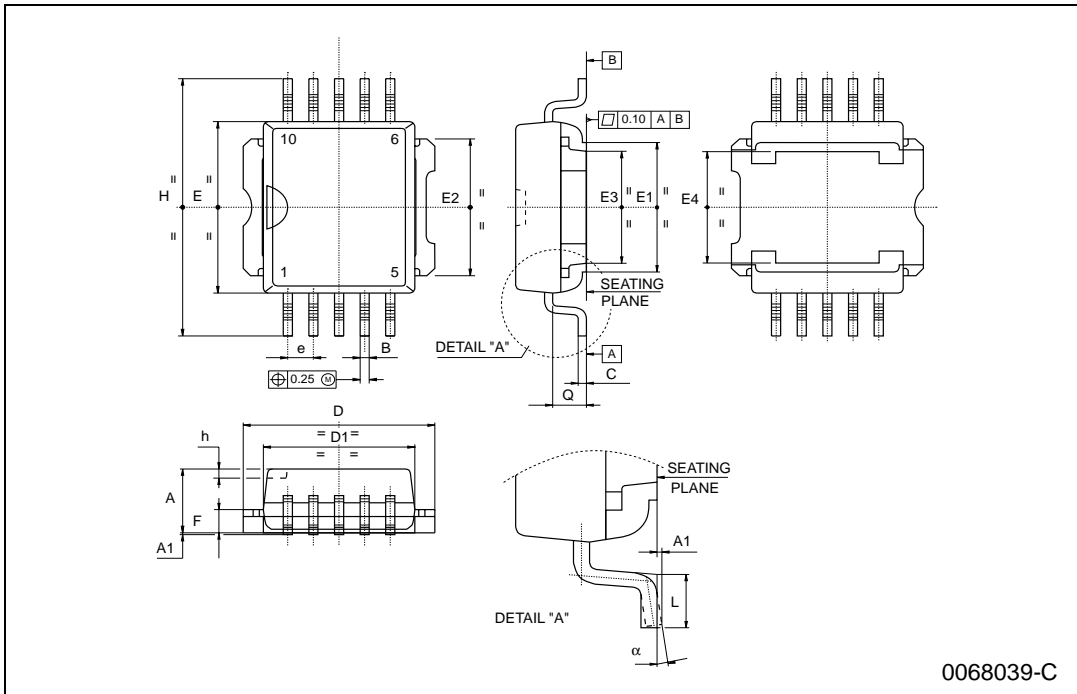


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times



**PowerSO-10 MECHANICAL DATA**

| DIM.     | mm    |      |       | inch  |       |       |
|----------|-------|------|-------|-------|-------|-------|
|          | MIN.  | TYP. | MAX.  | MIN.  | TYP.  | MAX.  |
| A        | 3.35  |      | 3.65  | 0.132 |       | 0.144 |
| A1       | 0.00  |      | 0.10  | 0.000 |       | 0.004 |
| B        | 0.40  |      | 0.60  | 0.016 |       | 0.024 |
| C        | 0.35  |      | 0.55  | 0.013 |       | 0.022 |
| D        | 9.40  |      | 9.60  | 0.370 |       | 0.378 |
| D1       | 7.40  |      | 7.60  | 0.291 |       | 0.300 |
| e        |       | 1.27 |       |       | 0.050 |       |
| E        | 9.30  |      | 9.50  | 0.366 |       | 0.374 |
| E1       | 7.20  |      | 7.40  | 0.283 |       | 0.291 |
| E2       | 7.20  |      | 7.60  | 0.283 |       | 0.300 |
| E3       | 6.10  |      | 6.35  | 0.240 |       | 0.250 |
| E4       | 5.90  |      | 6.10  | 0.232 |       | 0.240 |
| F        | 1.25  |      | 1.35  | 0.049 |       | 0.053 |
| h        |       | 0.50 |       |       | 0.002 |       |
| H        | 13.80 |      | 14.40 | 0.543 |       | 0.567 |
| L        | 1.20  |      | 1.80  | 0.047 |       | 0.071 |
| q        |       | 1.70 |       |       | 0.067 |       |
| $\alpha$ | 0°    |      | 8°    |       |       |       |



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